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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT****Complete if Known**

Application Number	10/570,054
Filing Date	February 28, 2006
First Named Inventor	Mi Wang
Art Unit	2863
Examiner Name	Teixeira Moffat,
Attorney Docket Number	7095UL-1 Jonathan C.

Sheet	1	of	1
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U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number Number-kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee of Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-4,298,936	11-03-1981	SHAPIRO, Gerald N.	
		US-4,438,488	03-20-1984	SHIBAYAMA, Shigeki et al.	
		US-5,311,878	05-17-1994	BROWN, Brian H. et al.	
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ ; Number ⁴ ; Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
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OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

Examiner Initials*	Cite No. ¹	
		G. P. Lucas et al., "Measurement of the solids volume fraction and velocity distributions in solids-liquid flows using dual-plane electrical resistance tomography", Flow Measurement and Instrumentation, vol. 10, 1999, pp. 249-258; XP008040707, p. 250, left-hand column, last paragraph - p. 252, left-hand column.
		B. S. Hoyle et al., "Design and application of a multi-modal process tomography system" Measurement Science and Technology, vol. 12, 2001, pp. 1157-1165; XP008040617 abstract.
		M. Wang et al. "Characterization of gas-water flow using electrical resistance imaging" 11 th International Conference on Multiphase 03, June 13, 2003, pp. 595-604; XP008040620, Italy, p. 598.

Examiner Signature	/Jonathan Teixeira Moffat/	Date Considered	09/21/2010
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*EXAMINER: Initial if reference is considered, whether or not citation is in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /J.T.M.